

Impact of orientation on the bias of SRAM-based PUFs

Abideen, Zain Ul; Wang, Rui; **Perez, Tiago Diadami**; Schrijen, Geert-Jan; **Pagliarini, Samuel Nascimento** IEEE design & test 2024 / p. 14-20 <https://doi.org/10.1109/MDAT.2023.3322621> [Journal metrics at Scopus](#) [Article at Scopus](#) [Journal metrics at WOS](#) [Article at WOS](#)

Novel architectures for contractive autoencoders with embedded learning

Kerner, Madis; **Tammemäe, Kalle**; **Raik, Jaan**; **Hollstein, Thomas** 2020 17th Biennial Baltic electronics conference, Tallinn, Estonia, October 6-8, 2020 : proceedings 2020 / 6 p. : ill <https://doi.org/10.1109/BEC49624.2020.9277246>